

FEATURES

- TIA/EIA RS-485 compliant over full supply range
- 3.0 V to 5.5 V operating voltage range on V_{CC}
- 1.62 V to 5.5 V V_{IO} logic supply
- ESD protection on the bus pins
 - IEC 61000-4-2 $\geq \pm 12$ kV contact discharge
 - IEC 61000-4-2 $\geq \pm 12$ kV air discharge
 - HBM $\geq \pm 30$ kV
- Full hot swap support (glitch free power-up/power-down)
- High-speed 50 Mbps data rate (ADM3065E/ADM3066E)
- Low speed 500 kbps data rate for long cables (ADM3061E/ADM3062E)
- Full receiver short-circuit, open circuit, and bus idle fail-safe
- Extended temperature range up to 125°C
- Profibus compliant at $V_{CC} \geq 4.5$ V
- Half duplex
- Allows connection of up to 128 nodes onto the bus
- Space-saving package options
 - 10-lead, 3 mm \times 3 mm LFCSP
 - 8-lead and 10-lead MSOP
 - 8-lead, narrow body SOIC package

APPLICATIONS

- Industrial fieldbuses
- Process control
- Building automation
- Profibus networks
- Motor control servo drives and encoders

FUNCTIONAL BLOCK DIAGRAMS

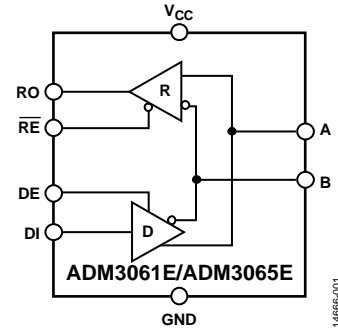


Figure 1. ADM3061E/ADM3065E Functional Block Diagram

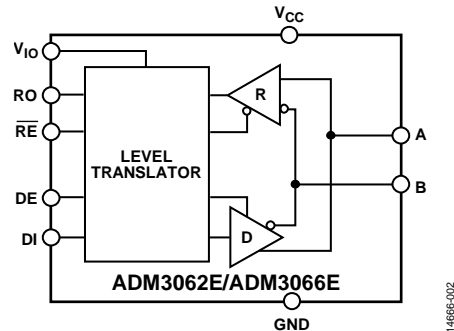


Figure 2. ADM3062E/ADM3066E Functional Block Diagram

Table 1. Summary of the ADM3061E/ADM3062E/ADM3065E/ADM3066E Operating Conditions—Data Rate Capability Across Temperature, Power Supply, and Package

Maximum Data Rate ¹	Maximum V_{CC} (V)	Maximum Temperature	Package Description
50 Mbps	5.5	-40°C to +125°C	10-lead LFCSP
50 Mbps	5.5	-40°C to +105°C	8-lead SOIC_N, 8-lead MSOP, and 10-lead MSOP
50 Mbps	3.6	-40°C to +125°C	8-lead SOIC_N, 8-lead MSOP, and 10-lead MSOP
500 kbps	5.5	-40°C to +125°C	8-lead SOIC_N, 8-lead MSOP, 10-lead MSOP, 10-lead LFCSP

¹ The ADM3065E/ADM3066E data input (DI) is transmitting 50 Mbps (or 500 kbps for the ADM3061E/ADM3062E) clock data, and the ADM3061E/ADM3062E/ADM3065E/ADM3066E driver enable (DE) is enabled for 50% of the DI transmit time.

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REVISION HISTORY

2/2018—Rev. B to Rev. C

Added ADM3062E	Universal
Changes to Figure 2 and Table 1	1
Changes to ADM3061E/ADM3062E Timing Specifications Section and Figure 3	6
Changes to Figure 5 and Figure 6	7
Changes to Figure 9 and Figure 10	11
Changes to Figure 16 and Figure 17	12
Changes to Figure 44.....	21
Changes to Figure 45.....	22
Changes to Ordering Guide.....	25

12/2017—Rev. A to Rev. B

Added ADM3061E.....	Universal
Changes to Product Title, Features Section, Figure 1, and Table 1... 1	
Changes to General Description Section	3
Changes to Table 2.....	4
Added ADM3061E Timing Specification Section and Table 3; Renumbered Sequentially.....	6
Moved Figure 3	6
Moved Figure 4, Figure 5, and Figure 6.....	7
Changes to ADM3065E/ADM3066E Timing Specification Section Title.....	8
Added 10-Lead MSOP Parameter and 10-Lead LFCSP Parameter, Table 5	9
Changes to Operating Temperature Range Parameter, Table 5 and Table 6.....	9
Changes to Figure 7, Figure 8, and Table 7	10
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Changes to Figure 11	12
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Added Figure 24, Figure 25, Figure 26, Figure 27, and Figure 28... 14	
Changed High Speed IEC ESD Protected RS-485 Section to IEC ESD Protected RS-485 Section	17
Changes to IEC ESD Protected RS-485 Section	17
Added Endnote 4, Table 9	18
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Changes to Figure 44.....	21
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Changes to Ordering Guide.....	25

5/2017—Rev. 0 to Rev. A

Added ADM3066E.....	Universal
Changes to Features Section, Figure 1, and Table 1	1
Added Figure 2; Renumbered Sequentially	1
Moved General Description Section.....	3
Changes to General Description Section	3
Changes to Specifications Section and Table 2.....	4
Changes to Timing Specifications Section and Figure 3.....	5
Changes to Figure 4, Figure 5, and Figure 6	6
Added V _{IO} to GND Parameter, Table 4.....	7
Changes to Thermal Resistance Section and Table 5	7
Added Figure 8.....	8
Changes to Table 6.....	8
Added Figure 9 and Figure 10	9
Added Table 7; Renumbered Sequentially	9
Changes to Figure 14, Figure 16, and Figure 17	10
Changes to Table 8 and Table 9	15
Added Figure 42 and Figure 43	20
Changes to Ordering Guide	21

3/2017—Revision 0: Initial Version

GENERAL DESCRIPTION

The ADM3065E is a 3.0 V to 5.5 V, IEC electrostatic discharge (ESD) protected RS-485 transceiver, allowing the device to withstand ± 12 kV contact discharges on the transceiver bus pins without latch-up or damage. The ADM3066E/ADM3062E features a V_{IO} logic supply pin allowing a flexible digital interface capable of operating as low as 1.62 V.

The ADM3065E/ADM3066E are suitable for high speed, 50 Mbps, bidirectional data communication on multipoint bus transmission lines. The

ADM3061E/ADM3062E/ADM3065E/ADM3066E feature a $\frac{1}{4}$ unit load input impedance, which allows up to 128 transceivers on a bus. The ADM3061E/ADM3062E models offer all of the same features as the ADM3065E/ADM3066E models, but at a low 500 kbps data rate suitable for operation over long cable runs.

The ADM3061E/ADM3062E/ADM3065E/ADM3066E are half-duplex RS-485 transceivers, fully compliant to the Profibus® standard with increased 2.1 V bus differential voltage at $V_{CC} \geq 4.5$ V.

The RS-485 transceivers are available in a number of space-saving packages, such as a 10-lead, 3 mm \times 3 mm LFCSP, an 8-lead, 3 mm \times 3 mm MSOP, a 10-lead, 3 mm \times 3 mm MSOP, and an 8-lead, narrow body SOIC package. Models with operating temperature ranges of -40°C to $+125^{\circ}\text{C}$ and -40°C to $+85^{\circ}\text{C}$ are available.

Excessive power dissipation caused by bus contention or by output shorting is prevented by a thermal shutdown circuit. If, during fault conditions, a significant temperature increase is detected in the internal driver circuitry, this feature forces the driver output into a high impedance state.

The ADM3061E/ADM3062E/ADM3065E/ADM3066E guarantee a logic high receiver output when the receiver inputs are shorted, open, or connected to a terminated transmission line with all drivers disabled.

Table 1 presents an overview of the ADM3061E/ADM3062E/ADM3065E/ADM3066E data rate capability across temperature, power supply, and package options. Refer to the Ordering Guide for model numbering.

SPECIFICATIONS

$V_{CC} = 3.0\text{ V}$ to 5.5 V , $V_{IO} = 1.62\text{ V}$ to V_{CC} , $T_A = T_{MIN} (-40^\circ\text{C})$ to $T_{MAX} (+125^\circ\text{C})$, unless otherwise noted. All typical specifications are at $T_A = 25^\circ\text{C}$, $V_{IO} = V_{CC} = 3.3\text{ V}$ unless otherwise noted.

Table 2.

Parameter	Symbol	Min	Typ	Max	Unit	Test Conditions/Comments
POWER SUPPLY						
Supply Current	I_{CC}		2	7.5	mA	No load, $DE = V_{CC}$, $\overline{RE} = 0\text{ V}$
				7.5	mA	No load, $DE = V_{CC}$, $\overline{RE} = V_{CC}$
				4.5	mA	No load, $DE = 0\text{ V}$, $\overline{RE} = 0\text{ V}$
				172	mA	50 Mbps, load resistance (R_L) = $54\ \Omega$, $DE = V_{CC}$, $\overline{RE} = 0\text{ V}$
			67	75	mA	50 Mbps, $R_L = 54\ \Omega$, $DE = V_{CC}$, $\overline{RE} = 0\text{ V}$ ($V_{CC} = 3.0\text{ V}$)
				165	mA	500 kbps, $R_L = 54\ \Omega$, $DE = V_{CC}$, $\overline{RE} = 0\text{ V}$
				74	mA	500 kbps, $R_L = 54\ \Omega$, $DE = V_{CC}$, $\overline{RE} = 0\text{ V}$ ($V_{CC} = 3.0\text{ V}$)
Supply Current in Shutdown Mode	I_{SHDN}			450	μA	$DE = 0\text{ V}$, $\overline{RE} = V_{CC}$
V_{IO} Shutdown Current	I_{IOSHDN}			50	μA	$DE = 0\text{ V}$, $\overline{RE} = V_{IO}$
DRIVER						
Differential Outputs						
Output Voltage, Loaded	$ V_{OD2} $		2.0	V_{CC}	V	$V_{CC} \geq 3.0\text{ V}$, $R_L = 50\ \Omega$, see Figure 11
			1.5	V_{CC}	V	$V_{CC} \geq 3.0\text{ V}$, $R_L = 27\ \Omega$ (RS-485), see Figure 11
			2.1	V_{CC}	V	$V_{CC} \geq 4.5\text{ V}$, $R_L = 50\ \Omega$, see Figure 11
			2.1	V_{CC}	V	$V_{CC} \geq 4.5\text{ V}$, $R_L = 27\ \Omega$ (RS-485), see Figure 11
			1.5	V_{CC}	V	$V_{CC} \geq 3.0\text{ V}$, $-7\text{ V} \leq V_{CM} \leq +12\text{ V}$, see Figure 12
			2.1	V_{CC}	V	$V_{CC} \geq 4.5\text{ V}$, $-7\text{ V} \leq V_{CM} \leq +12\text{ V}$, see Figure 12
$\Delta V_{OD} $ for Complementary Output States	$\Delta V_{OD} $			0.2	V	$R_L = 27\ \Omega$ or $50\ \Omega$, see Figure 11
Common-Mode Output Voltage	V_{OC}			3.0	V	$R_L = 27\ \Omega$ or $50\ \Omega$, see Figure 11
$\Delta V_{OC} $ for Complementary Output States	$\Delta V_{OC} $			0.2	V	$R_L = 27\ \Omega$ or $50\ \Omega$, see Figure 11
Output Short-Circuit Current	I_{OS}	-250		250	mA	$-7\text{ V} < \text{output voltage } (V_{OUT}) < +12\text{ V}$
Logic Inputs (DE, \overline{RE} , DI)						
Input Voltage						
Low	V_{IL}			$0.33 \times V_{IO}$	V	DE, \overline{RE} , DI, $1.62\text{ V} \leq V_{IO} \leq 5.5\text{ V}$
High	V_{IH}	$0.67 \times V_{IO}$			V	DE, \overline{RE} , DI, $1.62\text{ V} \leq V_{IO} \leq 5.5\text{ V}$
Input Current	I_I	-2		+2	μA	DE, \overline{RE} , DI, $1.62\text{ V} \leq V_{IO} \leq 5.5\text{ V}$, $0\text{ V} \leq \text{input voltage } (V_{IN}) \leq V_{IO}$

Parameter	Symbol	Min	Typ	Max	Unit	Test Conditions/Comments
RECEIVER						
Differential Inputs						
Differential Input Threshold Voltage	V_{TH}	-200	-125	-30	mV	$-7\text{ V} < \text{common-mode voltage } (V_{CM}) < +12\text{ V}$
Input Voltage Hysteresis	V_{HYS}		30		mV	$-7\text{ V} < V_{CM} < +12\text{ V}$
Input Current (A, B)	I_I			0.25	mA	$DE = 0\text{ V}, V_{CC} = \text{powered/unpowered}, V_{IN} = 12\text{ V}$
		-0.20			mA	$DE = 0\text{ V}, V_{CC} = \text{powered/unpowered}, V_{IN} = -7\text{ V}$
Line Input Resistance	R_{IN}	48			k Ω	$-7\text{ V} \leq V_{CM} \leq +12\text{ V}$
Logic Outputs						
Output Voltage						
Low	V_{OL}			0.4	V	$V_{IO} = 3.6\text{ V}, I_{OUT} = +2\text{ mA}, V_{ID}^1 \leq -0.2\text{ V}$
				0.4	V	$V_{IO} = 2.7\text{ V}, I_{OUT} = +1\text{ mA}, V_{ID} \leq -0.2\text{ V}$
				0.2	V	$V_{IO} = 1.95\text{ V}, I_{OUT} = +500\text{ }\mu\text{A}, V_{ID} \leq -0.2\text{ V}$
High	V_{OH}	2.4			V	$V_{IO} = 3.0\text{ V}, I_{OUT} = -2\text{ mA}, V_{ID} \geq +0.2\text{ V}$
		2.0			V	$V_{IO} = 2.3\text{ V}, I_{OUT} = -1\text{ mA}, V_{ID} \geq +0.2\text{ V}$
		$V_{IO} - 0.2$			V	$V_{IO} = 1.65\text{ V}, I_{OUT} = -500\text{ }\mu\text{A}, V_{ID} \geq +0.2\text{ V}$
Short-Circuit Current				85	mA	$V_{OUT} = \text{GND or } V_{CC}$
Three-State Output Leakage	I_{OZR}			± 2	μA	$RO = 0\text{ V or } V_{CC}$

¹ V_{ID} is the receiver input differential voltage.

ADM3061E/ADM3062E TIMING SPECIFICATIONS

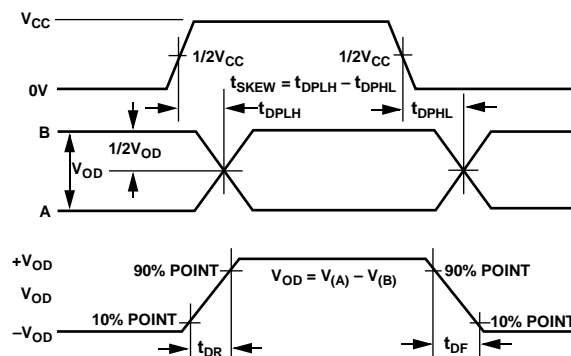
$V_{CC} = 3.0\text{ V to }5.5\text{ V}$, $V_{IO} = 1.62\text{ V to }V_{CC}$, $T_A = T_{MIN} (-40^{\circ}\text{C})\text{ to }T_{MAX} (+125^{\circ}\text{C})$, unless otherwise noted. All typical specifications are at $T_A = 25^{\circ}\text{C}$, $V_{IO} = V_{CC} = 3.3\text{ V}$, unless otherwise noted.

Table 3.

Parameter	Symbol	Min	Typ	Max	Unit	Test Conditions/Comments
DRIVER						
Maximum Data Rate ¹		500			kbps	
Propagation Delay	t_{DPLH}, t_{DPHL}		220	800	ns	$R_{LDIFF} = 54\ \Omega, C_{L1} = C_{L2} = 100\text{ pF}$, see Figure 13
Skew	t_{DSKEW}		5	100	ns	$R_{LDIFF} = 54\ \Omega, C_{L1} = C_{L2} = 100\text{ pF}$, see Figure 13
Rise/Fall Times	t_{DR}, t_{DF}	120		800	ns	$R_{LDIFF} = 54\ \Omega, C_{L1} = C_{L2} = 100\text{ pF}$, see Figure 13
Enable to Output High	t_{DZH}			1000	ns	$R_L = 110\ \Omega, C_L = 50\text{ pF}$, see Figure 14
Enable to Output Low	t_{DZL}			1000	ns	$R_L = 110\ \Omega, C_L = 50\text{ pF}$, see Figure 14
Disable Time from Low	t_{DLZ}			2000	ns	$R_L = 110\ \Omega, C_L = 50\text{ pF}$, see Figure 14
Disable Time from High	t_{DHZ}			2000	ns	$R_L = 110\ \Omega, C_L = 50\text{ pF}$, see Figure 14
Enable Time from Shutdown to High	$t_{DZH(SHDN)}$			2000	ns	$R_L = 110\ \Omega, C_L = 50\text{ pF}$, see Figure 14
Enable Time from Shutdown to Low	$t_{DZL(SHDN)}$			2000	ns	$R_L = 110\ \Omega, C_L = 50\text{ pF}$, see Figure 14
RECEIVER						
Maximum Data Rate		500			Kbps	
Propagation Delay	t_{RPLH}, t_{RPHL}			200	ns	$C_L = 15\text{ pF}, V_{ID} \geq 1.5\text{ V}$, see Figure 15
Skew/Pulse Width Distortion	t_{RSKEW}			50	ns	$C_L = 15\text{ pF}, V_{ID} \geq 1.5\text{ V}, V_{CM} = 1.5\text{ V}$, see Figure 15
Enable to Output High	t_{RZH}		10	50	ns	$R_L = 1\text{ k}\Omega, C_L = 15\text{ pF}, V_{ID} \geq 1.5\text{ V}$, DE high, see Figure 17
Enable to Output Low	t_{RZL}		10	50	ns	$R_L = 1\text{ k}\Omega, C_L = 15\text{ pF}, V_{ID} \geq 1.5\text{ V}$, DE high, see Figure 17
Disable Time from Low	t_{RLZ}		10	50	ns	$R_L = 1\text{ k}\Omega, C_L = 15\text{ pF}, V_{ID} \geq 1.5\text{ V}$, see Figure 17
Disable Time from High	t_{RHZ}		10	50	ns	$R_L = 1\text{ k}\Omega, C_L = 15\text{ pF}, V_{ID} \geq 1.5\text{ V}$, see Figure 17
Enable from Shutdown to High	$t_{RZH(SHDN)}$			2000	ns	$R_L = 1\text{ k}\Omega, C_L = 15\text{ pF}, V_{ID} \geq 1.5\text{ V}$, see Figure 16
Enable from Shutdown to Low	$t_{RZL(SHDN)}$			2000	ns	$R_L = 1\text{ k}\Omega, C_L = 15\text{ pF}, V_{ID} \geq 1.5\text{ V}$, see Figure 16
TIME TO SHUTDOWN	t_{SHDN}	40			ns	

¹ Maximum data rate assumes a ratio of $t_{DR}:t_{BIT}:t_{DF}$ equal to 1:0.5:1.

Timing Diagrams

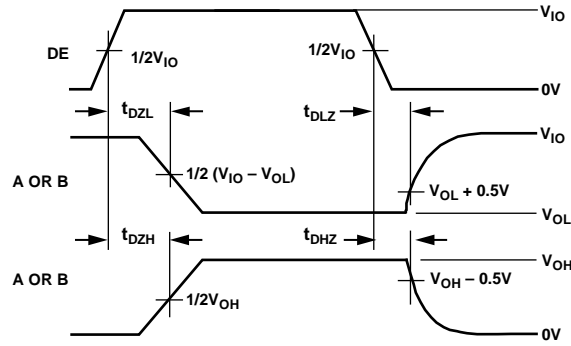


NOTES

- V_{OD} IS THE DIFFERENCE BETWEEN A AND B, WITH $+V_{OD}$ BEING THE MAXIMUM POINT OF V_{OD} , AND $-V_{OD}$ BEING THE MINIMUM POINT OF V_{OD} .
- $V_{CC} = V_{IO}$ FOR ADM3066E/ADM3062E.

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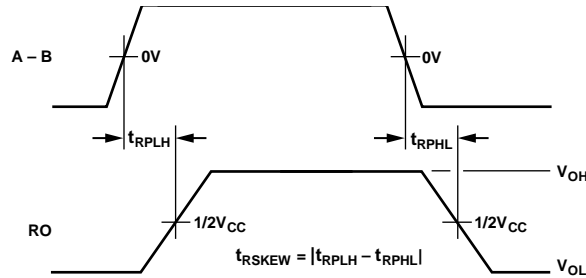
Figure 3. Driver Propagation Delay Rise and Fall Timing Diagram



NOTES
1. $V_{IO} = V_{CC}$ FOR ADM3065E/ADM3061E.

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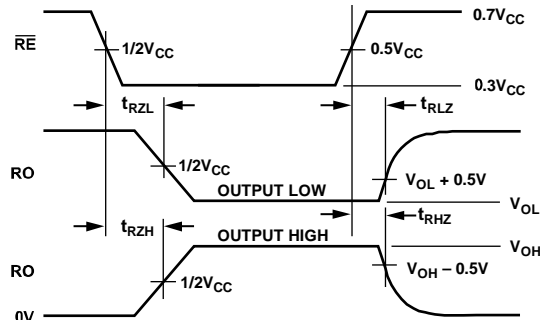
Figure 4. Driver Enable and Disable Timing Diagram



NOTES
1. $V_{CC} = V_{IO}$ FOR ADM3066E/ADM3062E.

14686-005

Figure 5. Receiver Propagation Delay Timing Diagram



NOTES
1. $V_{CC} = V_{IO}$ FOR ADM3066E/ADM3062E.

14686-006

Figure 6. Receiver Enable and Disable Timing Diagram

ADM3065E/ADM3066E TIMING SPECIFICATIONS

$V_{CC} = 3.0\text{ V to }5.5\text{ V}$, $V_{IO} = 1.62\text{ V to }V_{CC}$, $T_A = T_{MIN} (-40^\circ\text{C})$ to $T_{MAX} (+125^\circ\text{C})$, unless otherwise noted. All typical specifications are at $T_A = 25^\circ\text{C}$, $V_{IO} = V_{CC} = 3.3\text{ V}$, unless otherwise noted.

Table 4.

Parameter	Symbol	Min	Typ	Max	Unit	Test Conditions/Comments
DRIVER						
Maximum Data Rate ¹		50			Mbps	
Propagation Delay	t_{DPLH} , t_{DPHL}		9	15	ns	$R_{LDIFF} = 54\ \Omega$, $C_{L1} = C_{L2} = 100\text{ pF}$, see Figure 13
Skew	t_{DSKEW}		1	2	ns	$R_{LDIFF} = 54\ \Omega$, $C_{L1} = C_{L2} = 100\text{ pF}$, see Figure 13
Rise/Fall Times	t_{DR} , t_{DF}		4	6.7	ns	$R_{LDIFF} = 54\ \Omega$, $C_{L1} = C_{L2} = 100\text{ pF}$, see Figure 13
Enable to Output High	t_{DZH}		10	30	ns	$R_L = 110\ \Omega$, $C_L = 50\text{ pF}$, see Figure 14
Enable to Output Low	t_{DZL}		10	30	ns	$R_L = 110\ \Omega$, $C_L = 50\text{ pF}$, see Figure 14
Disable Time from Low	t_{DLZ}		10	30	ns	$R_L = 110\ \Omega$, $C_L = 50\text{ pF}$, see Figure 14
Disable Time from High	t_{DHZ}		10	30	ns	$R_L = 110\ \Omega$, $C_L = 50\text{ pF}$, see Figure 14
Enable Time from Shutdown to High	$t_{DZH(SHDN)}$			2000	ns	$R_L = 110\ \Omega$, $C_L = 50\text{ pF}$, see Figure 14
Enable Time from Shutdown to Low	$t_{DZL(SHDN)}$			2000	ns	$R_L = 110\ \Omega$, $C_L = 50\text{ pF}$, see Figure 14
RECEIVER						
Maximum Data Rate		50			Mbps	
Propagation Delay	t_{RPLH} , t_{RPHL}			35	ns	$C_L = 15\text{ pF}$, $ V_{ID} \geq 1.5\text{ V}$, see Figure 15
Skew/Pulse Width Distortion	t_{RSKEW}			3	ns	$C_L = 15\text{ pF}$, $ V_{ID} \geq 1.5\text{ V}$, $V_{CM} = 1.5\text{ V}$, see Figure 15
Enable to Output High	t_{RZH}		10	35	ns	$R_L = 1\text{ k}\Omega$, $C_L = 15\text{ pF}$, $ V_{ID} \geq 1.5\text{ V}$, DE high, see Figure 17
Enable to Output Low	t_{RZL}		10	35	ns	$R_L = 1\text{ k}\Omega$, $C_L = 15\text{ pF}$, $ V_{ID} \geq 1.5\text{ V}$, DE high, see Figure 17
Disable Time from Low	t_{RLZ}		10	35	ns	$R_L = 1\text{ k}\Omega$, $C_L = 15\text{ pF}$, $ V_{ID} \geq 1.5\text{ V}$, see Figure 17
Disable Time from High	t_{RHZ}		10	35	ns	$R_L = 1\text{ k}\Omega$, $C_L = 15\text{ pF}$, $ V_{ID} \geq 1.5\text{ V}$, see Figure 17
Enable from Shutdown to High	$t_{RZH(SHDN)}$			2000	ns	$R_L = 1\text{ k}\Omega$, $C_L = 15\text{ pF}$, $ V_{ID} \geq 1.5\text{ V}$, see Figure 16
Enable from Shutdown to Low	$t_{RZL(SHDN)}$			2000	ns	$R_L = 1\text{ k}\Omega$, $C_L = 15\text{ pF}$, $ V_{ID} \geq 1.5\text{ V}$, see Figure 16
TIME TO SHUTDOWN	t_{SHDN}	40			ns	

¹ Maximum data rate assumes a ratio of $t_{DR}:t_{BIT}:t_{DF}$ equal to 1:1:1.

ABSOLUTE MAXIMUM RATINGS

Table 5.

Parameter	Rating
V _{CC} to GND	6 V
V _{IO} to GND	-0.3 V to +6 V
Digital Input/Output Voltage (DE, $\overline{\text{RE}}$, DI, and RO)	-0.3 V to V _{CC} + 0.3 V
Driver Output/Receiver Input Voltage	-9 V to +14 V
Operating Temperature Range	-40°C to +85°C -40°C to +125°C
Storage Temperature Range	-65°C to +150°C
Continuous Total Power Dissipation	
8-Lead SOIC_N	0.225 W
8-Lead MSOP	0.151 W
10-Lead MSOP	0.151 W
10-Lead LFCSP	0.450 W
Maximum Junction Temperature	150°C
Lead Temperature	
Soldering (10 sec)	300°C
Vapor Phase (60 sec)	215°C
Infrared (15 sec)	220°C
ESD on the Bus Pins (A and B)	
IEC 61000-4-2 Contact Discharge	±12 kV
IEC 61000-4-2 Air Discharge	
Ten Positive and Ten Negative Discharges	±12 kV
Three Positive or Negative Discharges	±15 kV
ESD Human Body Model (HBM)	
On the Bus Pins (A and B)	>±30 kV
All Other Pins	±8 kV

Stresses at or above those listed under Absolute Maximum Ratings may cause permanent damage to the product. This is a stress rating only; functional operation of the product at these or any other conditions above those indicated in the operational section of this specification is not implied. Operation beyond the maximum operating conditions for extended periods may affect product reliability.

THERMAL RESISTANCE

Thermal performance is directly linked to printed circuit board (PCB) design and operating environment. Careful attention to PCB thermal design is required. θ_{JA} is the natural convection junction to ambient thermal resistance measured in a one cubic foot sealed enclosure. θ_{JC} is the junction to case thermal resistance.

Table 6. Thermal Resistance

Package Type	θ_{JA} ¹	θ_{JC} ¹	Unit
R-8	110.88	58.63	°C/W
RM-8	165.69	49.61	°C/W
RM-10	165.69	49.61	°C/W
CP-10-9	55.65	33.22	°C/W

¹ Thermal impedance simulated values are based on JEDEC 2S2P thermal test board with no bias. See JEDEC JESD-51.

ESD CAUTION



ESD (electrostatic discharge) sensitive device. Charged devices and circuit boards can discharge without detection. Although this product features patented or proprietary protection circuitry, damage may occur on devices subjected to high energy ESD. Therefore, proper ESD precautions should be taken to avoid performance degradation or loss of functionality.

PIN CONFIGURATIONS AND FUNCTION DESCRIPTIONS

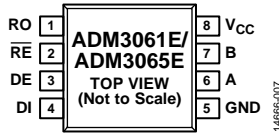


Figure 7. ADM3061E/ADM3065E 8-Lead Narrow Body SOIC_N Pin Configuration

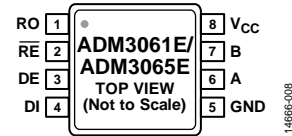
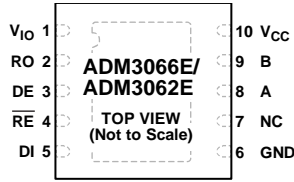


Figure 8. ADM3061E/ADM3065E 8-Lead MSOP Pin Configuration

Table 7. ADM3061E/ADM3065E Pin Function Descriptions

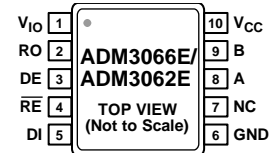
Pin No.	Mnemonic	Description
1	RO	Receiver Output Data. This output is high when $(A - B) \geq -30$ mV and low when $(A - B) \leq -200$ mV. This output is tristated when the receiver is disabled; that is, when \overline{RE} is driven high.
2	\overline{RE}	Receiver Enable Input. This is an active low input. Driving this input low enables the receiver, and driving it high disables the receiver.
3	DE	Driver Output Enable. A high level on this pin enables the driver differential outputs, A and B. A low level places the driver output into a high impedance state.
4	DI	Transmit Data Input. Data to be transmitted by the driver is applied to this input.
5	GND	Ground.
6	A	Noninverting Driver Output/Receiver Input. When the driver is disabled, or when V_{CC} is powered down, Pin A is put into a high impedance state to avoid overloading the bus.
7	B	Inverting Driver Output/Receiver Input. When the driver is disabled, or when V_{CC} is powered down, Pin B is put into a high impedance state to avoid overloading the bus.
8	V_{CC}	3.0V to 5.5V Power Supply. Adding a 0.1 μ F decoupling capacitor between the V_{CC} pin and the GND pin is recommended.



NOTES
 1. NC = NO CONNECT.
 2. EXPOSED PAD. THE EXPOSED PAD MUST BE CONNECTED TO GROUND.

14686-009

Figure 9. ADM3066E/ADM3062E 10-Lead LFCSP Pin Configuration



NOTES
 1. NC = NO CONNECT.

14686-010

Figure 10. ADM3066E/ADM3062E 10-Lead MSOP Pin Configuration

Table 8. ADM3066E/ADM3062E Pin Function Descriptions

Pin No.	Mnemonic	Description
1	V _{IO}	1.62 V to 5.5 V Logic Supply. Adding a 0.1 μF decoupling capacitor between the V _{IO} pin and the GND pin is recommended.
2	RO	Receiver Output Data. This output is high when (A – B) ≥ –30 mV and low when (A – B) ≤ –200 mV. This output is tristated when the receiver is disabled; that is, when RE is driven high.
3	DE	Driver Output Enable. A high level on this pin enables the driver differential outputs, A and B. A low level places the driver output into a high impedance state.
4	RE	Receiver Enable Input. This is an active low input. Driving this input low enables the receiver, and driving it high disables the receiver.
5	DI	Transmit Data Input. Data to be transmitted by the driver is applied to this input.
6	GND	Ground.
7	NC	No Connect. Do not connect to this pin.
8	A	Noninverting Driver Output/Receiver Input. When the driver is disabled, or when V _{CC} is powered down, Pin A is put into a high impedance state to avoid overloading the bus.
9	B	Inverting Driver Output/Receiver Input. When the driver is disabled, or when V _{CC} is powered down, Pin B is put into a high impedance state to avoid overloading the bus.
10	V _{CC}	3.0 V to 5.5 V Power Supply. Adding a 0.1 μF decoupling capacitor between the V _{CC} pin and the GND pin is recommended.
	EPAD	Exposed Pad. The exposed pad must be connected to ground.

TEST CIRCUITS

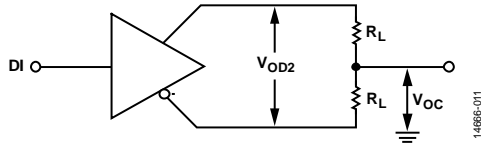


Figure 11. Driver Voltage Measurements

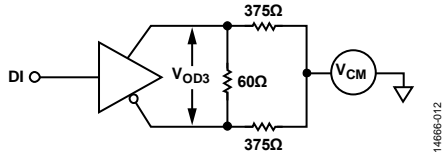


Figure 12. Driver Voltage Measurements over Common-Mode Range

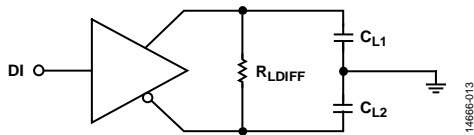
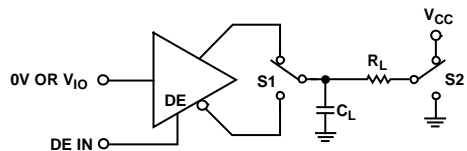


Figure 13. Driver Propagation Delay



NOTES
1. $V_{IO} = V_{CC}$ FOR ADM3065E/ADM3061E.

Figure 14. Driver Enable/Disable

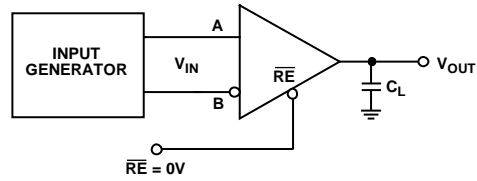
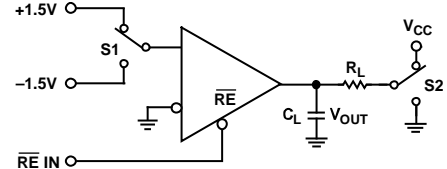
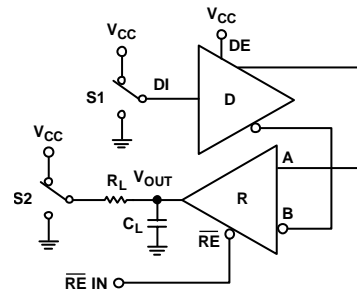


Figure 15. Receiver Propagation Delay/Skew



NOTES
1. $V_{CC} = V_{IO}$ FOR ADM3066E/ADM3062E.

Figure 16. Receiver Enable/Disable from Shutdown



NOTES
1. $V_{CC} = V_{IO}$ FOR ADM3066E/ADM3062E.

Figure 17. Receiver Enable/Disable

TYPICAL PERFORMANCE CHARACTERISTICS

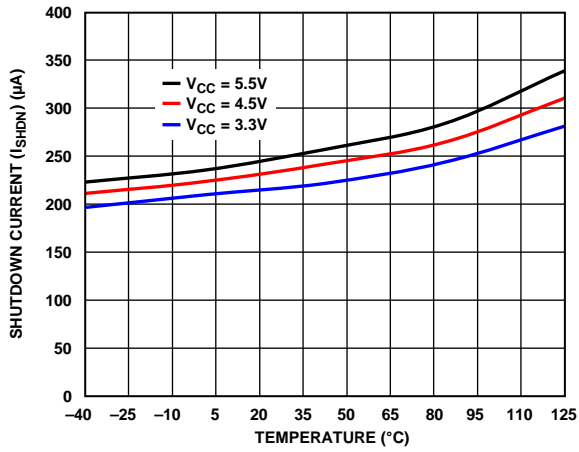


Figure 18. Shutdown Current (I_{SHDN}) vs. Temperature

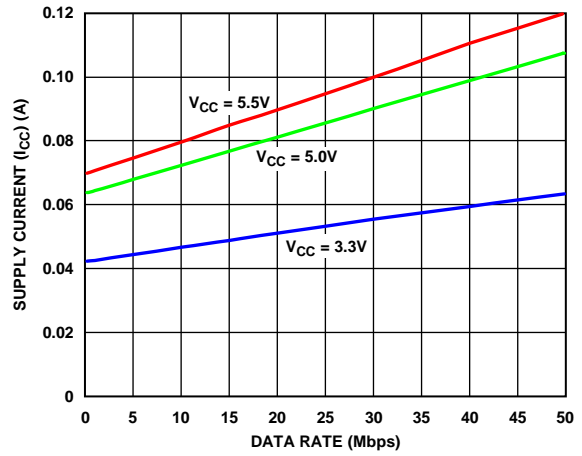


Figure 21. Supply Current (I_{CC}) vs. Data Rate with 54 Ω Load Resistance

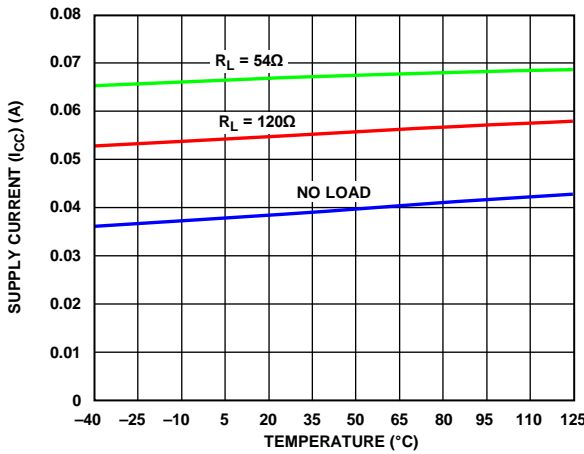


Figure 19. Supply Current (I_{CC}) vs. Temperature, Data Rate = 50 Mbps, V_{CC} = 3.3 V

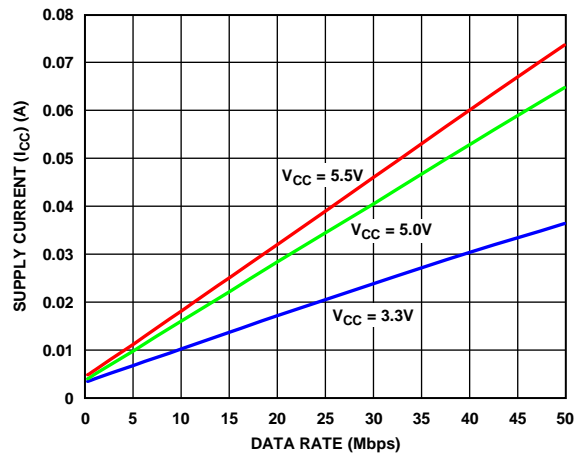


Figure 22. Supply Current (I_{CC}) vs. Data Rate with No Load Resistance

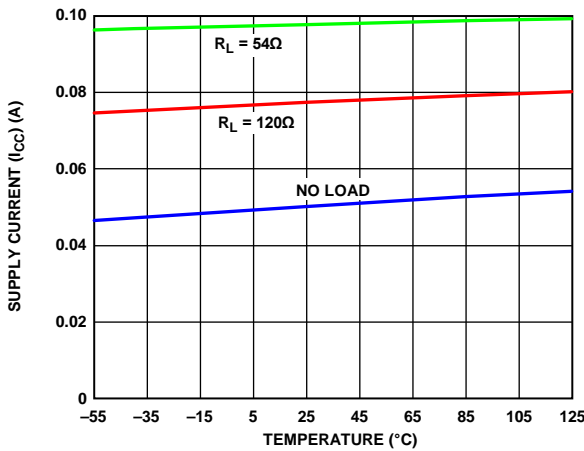


Figure 20. Supply Current (I_{CC}) vs. Temperature, Data Rate = 50 Mbps, V_{CC} = 5.0 V

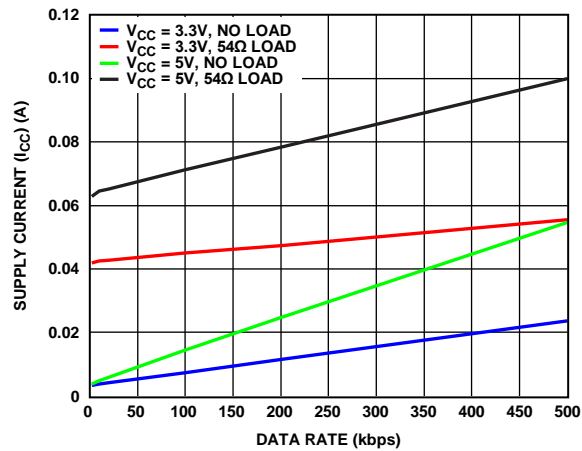


Figure 23. Supply Current (I_{CC}) vs. Data Rate with 54 Ω Load Resistance and No Load Resistance

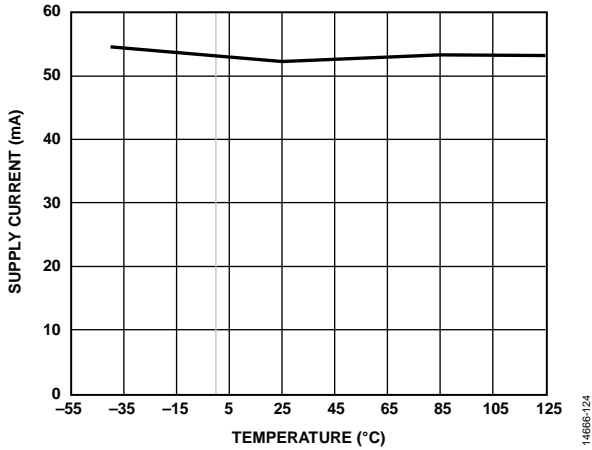


Figure 24. Supply Current (I_{CC}) vs. Temperature, Data Rate = 500 kbps, $V_{CC} = 3.0 V$

14666-124

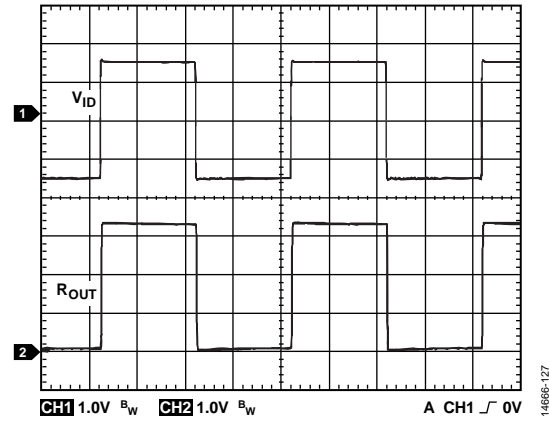


Figure 27. Receiver Propagation Delay (Oscilloscope Plot) 500 kbps $V_{ID} \geq 1.5 V$

14666-127

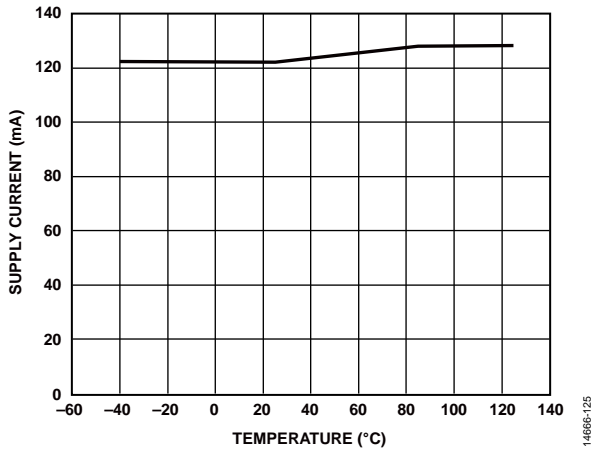


Figure 25. Supply Current (I_{CC}) vs. Temperature, Data Rate = 500 kbps, $V_{CC} = 5.5 V$

14666-125

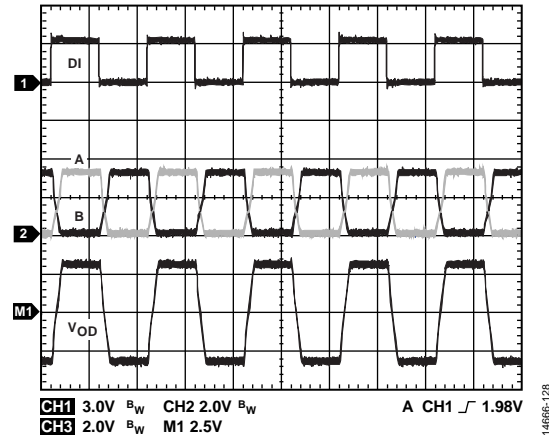


Figure 28. Driver Propagation Delay (Oscilloscope Plot) 500 kbps

14666-128

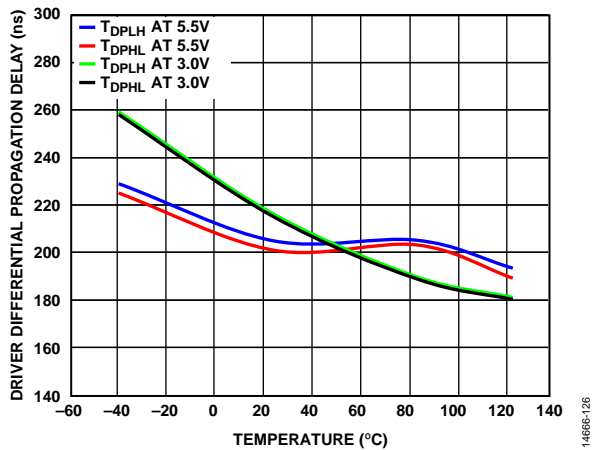


Figure 26. Driver Differential Propagation Delay vs. Temperature (500 kbps models)

14666-126

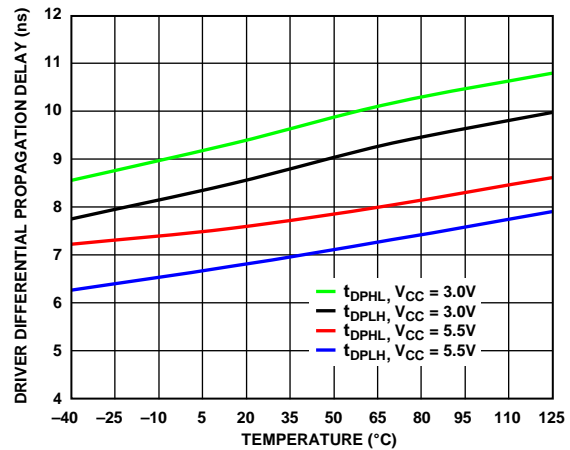


Figure 29. Driver Differential Propagation Delay vs. Temperature, 50 Mbps

14666-023

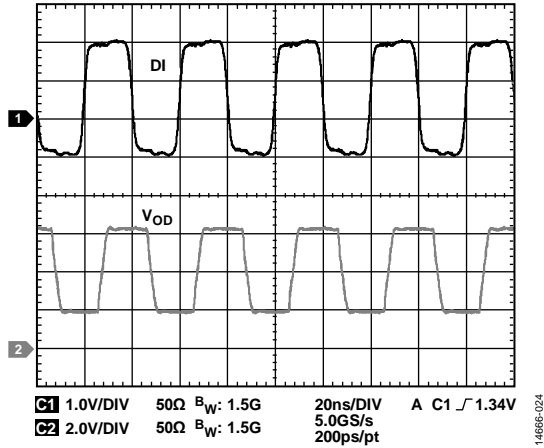


Figure 30. Driver Propagation Delay at 50 Mbps

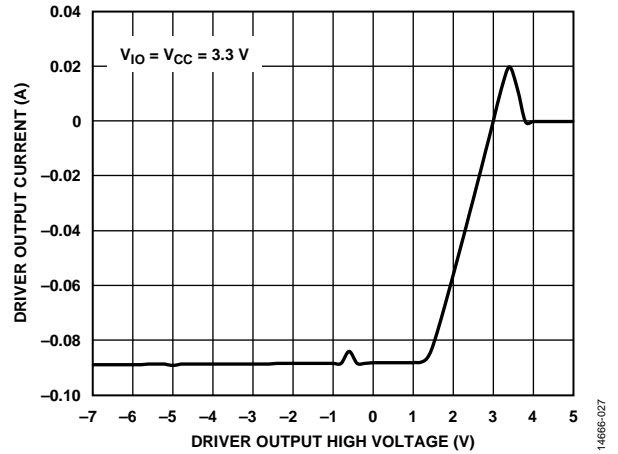


Figure 33. Driver Output Current vs. Driver Output High Voltage

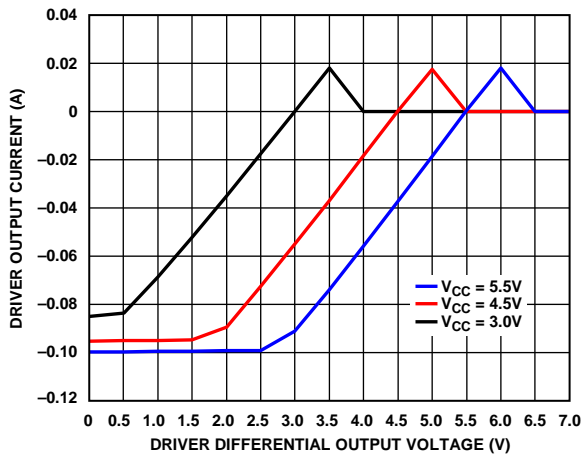


Figure 31. Driver Output Current vs. Driver Differential Output Voltage

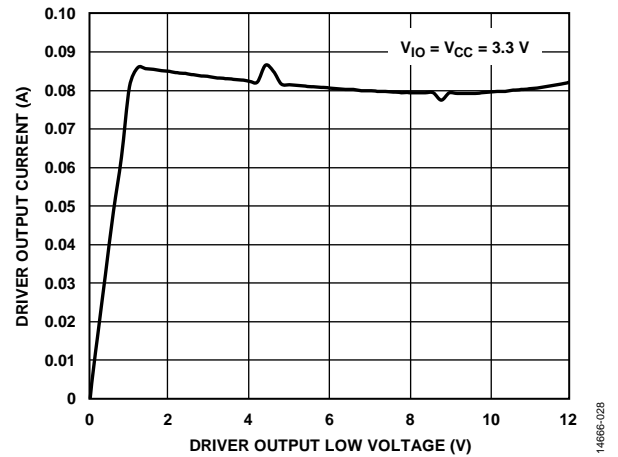


Figure 34. Driver Output Current vs. Driver Output Low Voltage

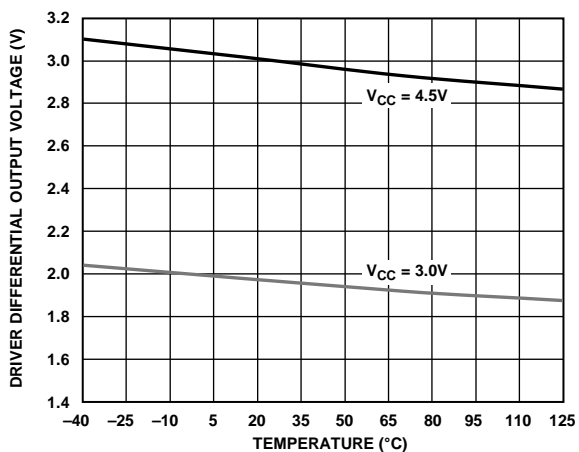


Figure 32. Driver Differential Output Voltage vs. Temperature

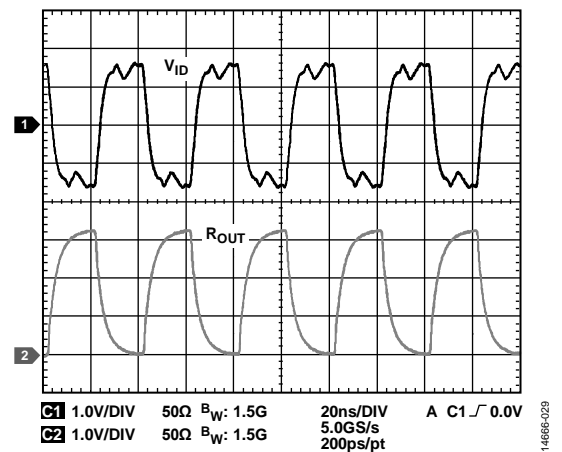


Figure 35. Receiver Propagation Delay at 50 Mbps, $|V_{ID}| \geq 1.5$ V

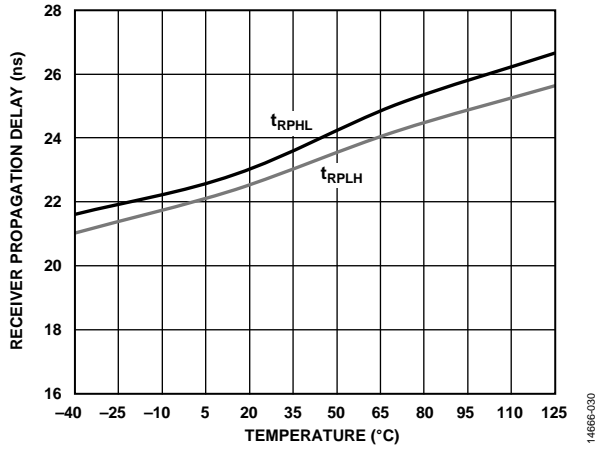


Figure 36. Receiver Propagation Delay vs. Temperature, 50 Mbps

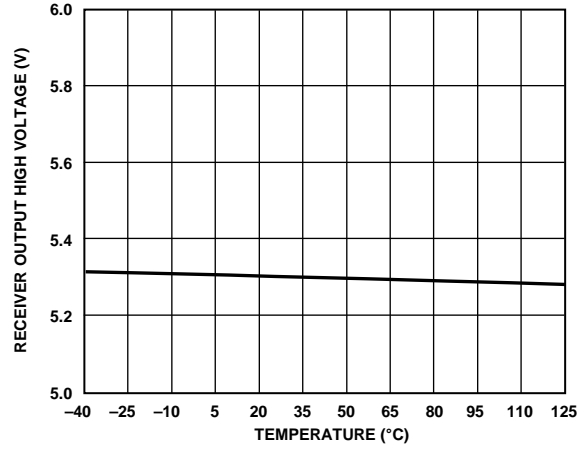


Figure 39. Receiver Output High Voltage vs. Temperature

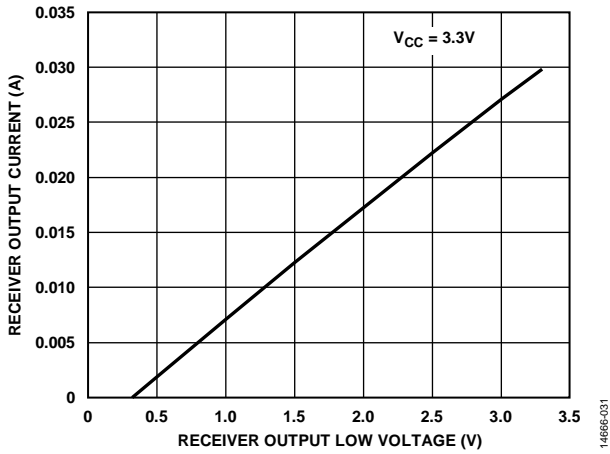


Figure 37. Receiver Output Current vs. Receiver Output Low Voltage ($V_{CC} = 3.3 V$)

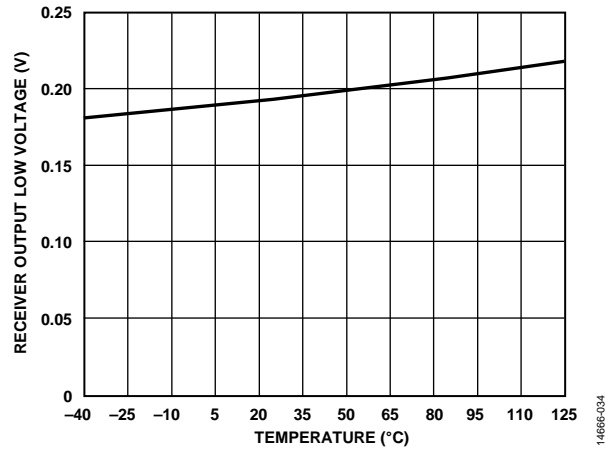


Figure 40. Receiver Output Low Voltage vs. Temperature

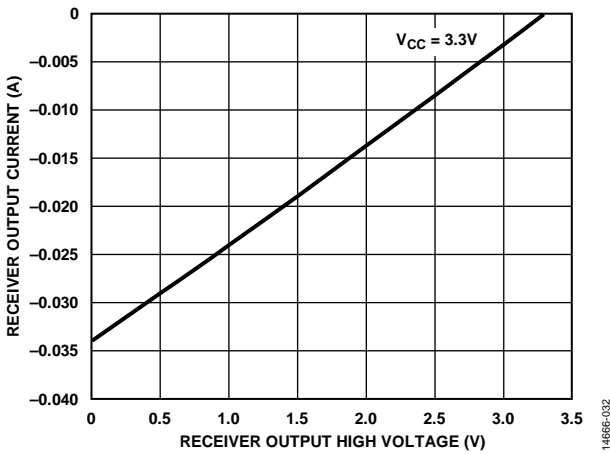


Figure 38. Receiver Output Current vs. Receiver Output High Voltage ($V_{CC} = 3.3 V$)

THEORY OF OPERATION

IEC ESD PROTECTED RS-485

The ADM3065E/ADM3066E are 3.0 V to 5.5 V, 50 Mbps RS-485 transceivers with IEC 61000-4-2 Level 4 ESD protection on the bus pins. The ADM3065E/ADM3066E can withstand up to ± 12 kV contact discharge on transceiver bus pins (A and B) without latch-up or damage. The ADM3061E/ADM3062E has the same robust IEC 61000-4-2 ESD protection as the ADM3065E/ADM3066E models and operate at a lower 500 kbps data rate.

HIGH DRIVER DIFFERENTIAL OUTPUT VOLTAGE

The ADM3061E/ADM3062E/ADM3065E/ADM3066E have characteristics optimized for use in Profibus applications. When powered at $V_{CC} \geq 4.5$ V, the ADM3061E/ADM3062E/ADM3065E/ADM3066E driver output differential voltage meets or exceeds the Profibus requirements of 2.1 V with a 54 Ω load.

IEC 61000-4-2 ESD PROTECTION

ESD is the sudden transfer of electrostatic charge between bodies at different potentials caused by near contact or induced by an electric field. It has the characteristics of high current in a short time period. The primary purpose of the IEC 61000-4-2 test is to determine the immunity of systems to external ESD events outside the system during operation. IEC 61000-4-2 describes testing using two coupling methods: contact discharge and air discharge. Contact discharge implies a direct contact between the discharge gun and the equipment under test (EUT). During air discharge testing, the charged electrode of the discharge gun is moved toward the EUT until a discharge occurs as an arc across the air gap. The discharge gun does not make direct contact with the EUT. A number of factors affect the results and repeatability of the air discharge test, including humidity, temperature, barometric pressure, distance, and rate of approach to the EUT. This method is a better representation of an actual ESD event but is not as repeatable. Therefore, contact discharge is the preferred test method.

During testing, the data port is subjected to at least 10 positive and 10 negative single discharges. Selection of the test voltage is dependent on the system end environment.

Figure 41 shows the 8 kV contact discharge current waveform as described in the IEC 61000-4-2 specification. Some of the key waveform parameters are rise times of less than 1 ns and pulse widths of approximately 60 ns.

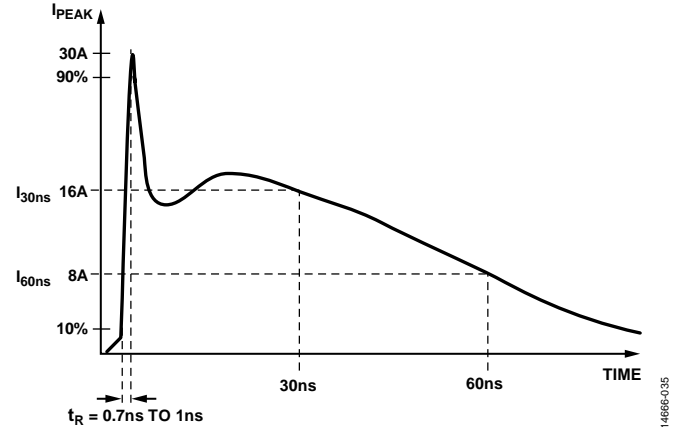


Figure 41. IEC 61000-4-2 ESD Waveform (8 kV)

Figure 42 shows the 8 kV contact discharge current waveform from the IEC 61000-4-2 standard compared to the HBM ESD 8 kV waveform. Figure 42 shows that the two standards specify a different waveform shape and peak current. The peak current associated with an IEC 61000-4-2 8 kV pulse is 30 A, whereas the corresponding peak current for HBM ESD is more than five times less, at 5.33 A. The other difference is the rise time of the initial voltage spike, with the IEC 61000-4-2 ESD waveform having a much faster rise time of 1 ns, compared to the 10 ns associated with the HBM ESD waveform. The amount of power associated with an IEC ESD waveform is much greater than that of an HBM ESD waveform. The HBM ESD standard requires the EUT to be subjected to three positive and three negative discharges, while in comparison, the IEC ESD standard requires 10 positive and 10 negative discharge tests.

The ADM3061E/ADM3062E/ADM3065E/ADM3066E with IEC 61000-4-2 ESD ratings is better suited for operation in harsh environments compared to other RS-485 transceivers that state varying levels of HBM ESD protection.

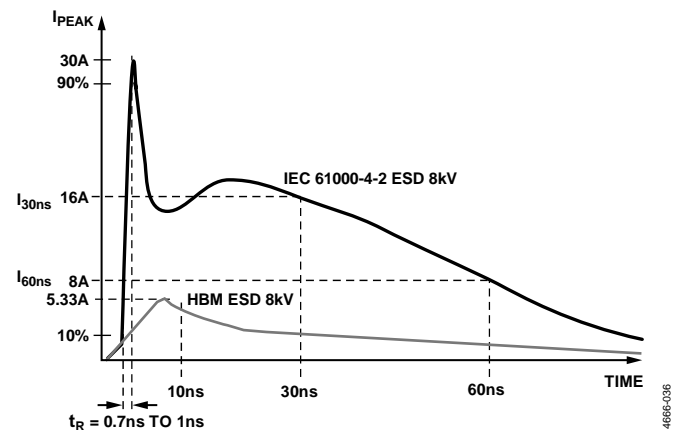


Figure 42. IEC 61000-4-2 ESD Waveform 8 kV Compared to HBM ESD Waveform 8 kV

TRUTH TABLES

Table 9. Transmitting Truth Table

Supply Status		Inputs			Outputs	
V _{IO} ⁴	V _{CC}	RE	DE	DI	A	B
On	On	X ¹	1	1	1	0
On	On	X ¹	1	0	0	1
On	On	0	0	X ¹	High-Z ²	High-Z ²
On	On	1	0	X ¹	High-Z ²	High-Z ²
On	Off	X ¹	1	1	I ³	I ³
On	Off	X ¹	1	0	I ³	I ³
On	Off	X ¹	0	X ¹	I ³	I ³
Off	On	X ¹	X ¹	X ¹	High-Z ²	High-Z ²
Off	Off	X ¹	X ¹	X ¹	High-Z ²	High-Z ²

¹ X means don't care.

² High-Z means high impedance.

³ I means indeterminate.

⁴ For the ADM3061E and ADM3065E, the V_{IO} pin is not applicable.

Table 10. Receiving Truth Table

Supply Status		Inputs	Outputs		
V _{IO} ⁴	V _{CC}	A – B	RE	DE	RO
On	On	>–0.03 V	0	X ¹	1
On	On	<–0.2 V	0	X ¹	0
Off	On	>–0.03 V	0	X ¹	I ³
Off	On	<–0.2 V	0	X ¹	I ³
On	On	–0.2 V ≤ A – B ≤ –0.03 V	0	X ¹	I ³
		–0.2 V ≤ A – B ≤ –0.03 V	0	X ¹	I ³
Off	On	–0.03 V	0	X ¹	I ³
On	On	Inputs open/shorted	0	X ¹	1
Off	On	Inputs open/shorted	0	X ¹	High-Z ²
On	On	X ¹	1	X ¹	High-Z ²
On	On	X ¹	1	0	Shutdown
Off	On	X ¹	1	X ¹	I ³
Off	Off	X ¹	X ¹	X ¹	High-Z ²

¹ X means don't care.

² High-Z means high impedance.

³ I means indeterminate.

⁴ For the ADM3061E and ADM3065E, the V_{IO} pin is not applicable.

RECEIVER FAIL-SAFE

The ADM3061E/ADM3062E/ADM3065E/ADM3066E guarantee a logic high receiver output when the receiver inputs are shorted, open, or connected to a terminated transmission line with all drivers disabled; set the receiver input threshold between –30 mV and –200 mV. If the differential receiver input voltage (A – B) is greater than or equal to –30 mV, the RO pin is logic high.

If the A – B input is less than or equal to –200 mV, RO is logic low. In the case of a terminated bus with all transmitters disabled, the receiver differential input voltage is pulled to 0 V by the termination, resulting in a logic high with a 30 mV minimum noise margin.

HOT SWAP CAPABILITY

Hot Swap Inputs

When a circuit board is inserted into a powered (or hot) backplane, differential disturbances to the data bus can lead to data errors. During this period, processor logic output drivers are high impedance and are unable to drive the DE and RE inputs of the RS-485 transceivers to a defined logic level. Leakage currents up to $\pm 10 \mu\text{A}$ from the high impedance state of the processor logic drivers can cause standard CMOS enable inputs of a transceiver to drift to an incorrect logic level. Additionally, parasitic circuit board capacitance can cause coupling of V_{CC} or GND to the enable inputs. Without the hot swap capability, these factors can improperly enable the driver or receiver of the transceiver. When V_{CC} or V_{IO} rises, an internal pull-down circuit holds DE low and RE high. After the initial power-up sequence, the pull-down circuit becomes transparent resetting the hot swap tolerable input.

128 TRANSCEIVERS ON THE BUS

The standard RS-485 receiver input impedance is $12 \text{ k}\Omega$ (1 unit load), and the standard driver can drive up to 32 unit loads. The ADM3061E/ADM3062E/ADM3065E/ADM3066E transceivers have a $\frac{1}{4}$ unit load receiver input impedance ($48 \text{ k}\Omega$), allowing up to 128 transceivers to be connected in parallel on one communication line. Any combination of these devices and other RS-485 transceivers with a total of 32 unit loads or fewer can be connected to the line.

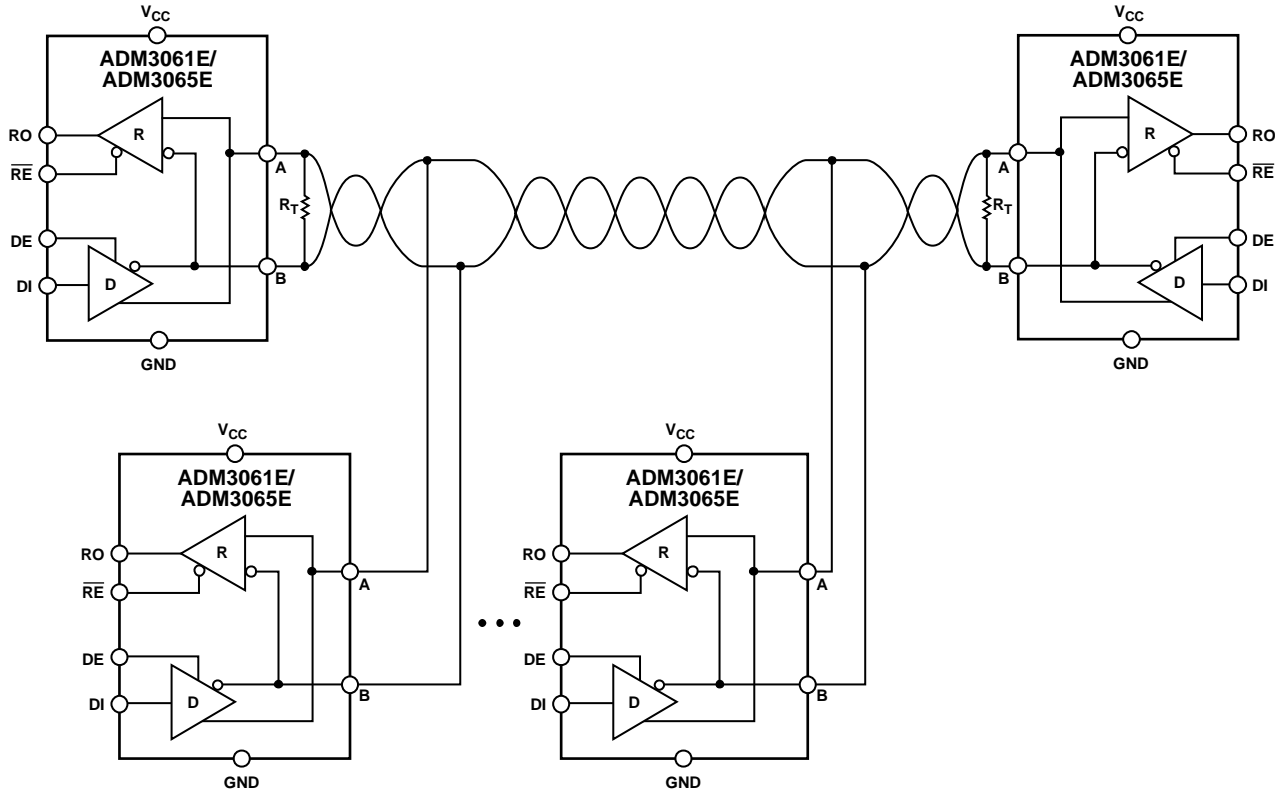
DRIVER OUTPUT PROTECTION

The ADM3061E/ADM3062E/ADM3065E/ADM3066E features two methods to prevent excessive output current and power dissipation caused by faults or by bus contention. Current-limit protection on the output stage provides immediate protection against short circuits over the whole common-mode voltage range. In addition, a thermal shutdown circuit forces the driver outputs into a high impedance state if the die temperature rises excessively. This circuitry is designed to disable the driver outputs when a die temperature of 150°C is reached. As the device cools, the drivers are reenabled at a temperature of 140°C .

APPLICATIONS INFORMATION

The ADM3061E/ADM3065E transceiver is designed for bidirectional data communications on multipoint bus transmission lines. Figure 43 shows a typical network applications circuit.

To minimize reflections, terminate the line at both ends with a termination resistor (the value of the termination resistor must be equal to the characteristic impedance of the cable used) and keep stub lengths off the main line as short as possible.



- NOTES**
1. THE MAXIMUM NUMBER OF NODES IS 128.
 2. R_T IS EQUAL TO THE CHARACTERISTIC IMPEDANCE OF THE CABLE USED.

Figure 43. ADM3061E/ADM3065E Typical Half-Duplex RS-485 Communications Network

14665-037

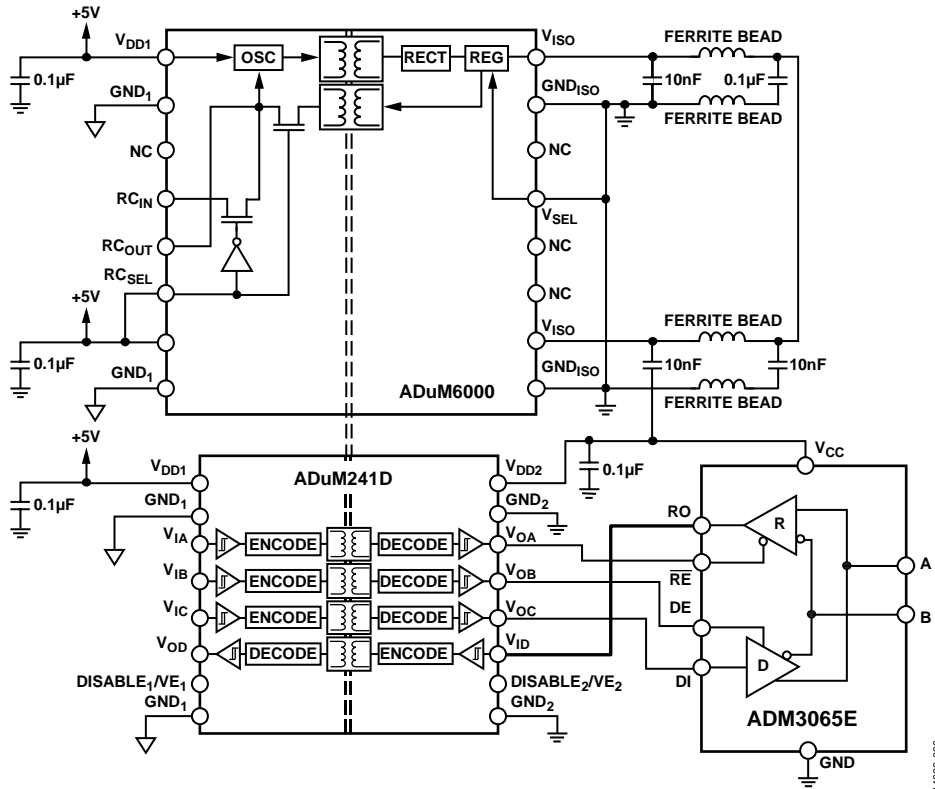
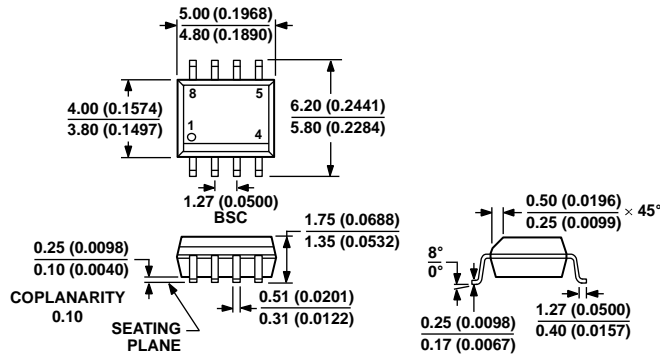


Figure 45. Signal and Power Isolated 50 Mbps RS-485 Solution (Simplified Diagram—All Connections Not Shown)

OUTLINE DIMENSIONS

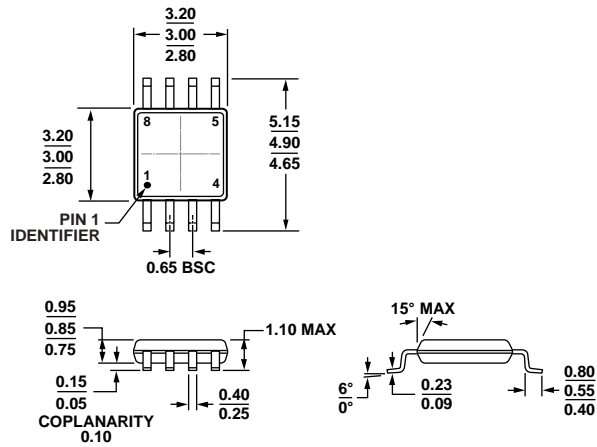


COMPLIANT TO JEDEC STANDARDS MS-012-AA
 CONTROLLING DIMENSIONS ARE IN MILLIMETERS; INCH DIMENSIONS
 (IN PARENTHESES) ARE ROUNDED-OFF MILLIMETER EQUIVALENTS FOR
 REFERENCE ONLY AND ARE NOT APPROPRIATE FOR USE IN DESIGN.

Figure 46. 8-Lead Standard Small Outline Package [SOIC_N]
 Narrow Body
 (R-8)

Dimensions shown in millimeters and (inches)

012A07-A

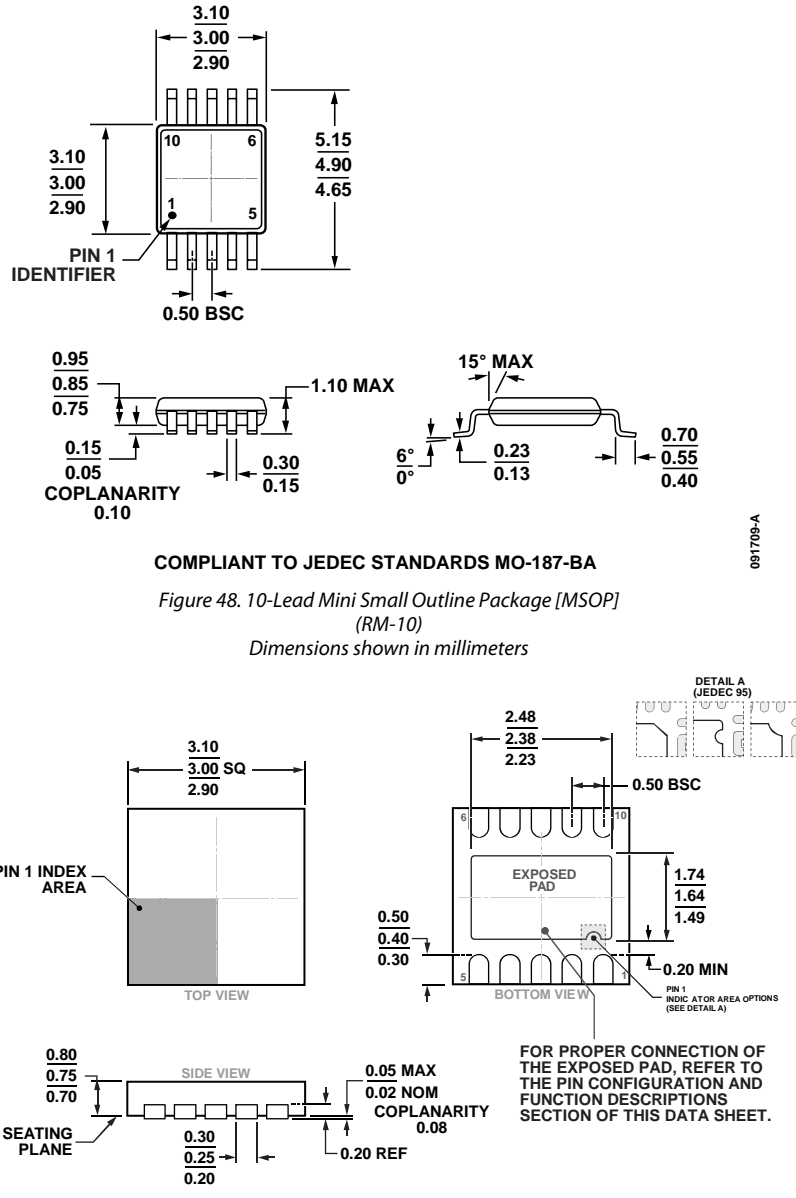


COMPLIANT TO JEDEC STANDARDS MO-187-AA

Figure 47. 8-Lead Mini Small Outline Package [MSOP]
 (RM-8)

Dimensions shown in millimeters

10-07-2008-B



ORDERING GUIDE

Model ¹	Temperature Range	Package Description	Package Option
ADM3061EARZ	-40°C to +85°C	8-Lead Standard Small Outline Package [SOIC_N]	R-8
ADM3061EARZ-R7	-40°C to +85°C	8-Lead Standard Small Outline Package [SOIC_N]	R-8
ADM3061EBRZ	-40°C to +125°C	8-Lead Standard Small Outline Package [SOIC_N]	R-8
ADM3061EBRZ-R7	-40°C to +125°C	8-Lead Standard Small Outline Package [SOIC_N]	R-8
ADM3061EARMZ	-40°C to +85°C	8-Lead Mini Small Outline Package [MSOP]	RM-8
ADM3061EARMZ-R7	-40°C to +85°C	8-Lead Mini Small Outline Package [MSOP]	RM-8
ADM3061EBRMZ	-40°C to +125°C	8-Lead Mini Small Outline Package [MSOP]	RM-8
ADM3061EBRMZ-R7	-40°C to +125°C	8-Lead Mini Small Outline Package [MSOP]	RM-8
ADM3062EACPZ	-40°C to +85°C	10-Lead Lead Frame Chip Scale Package [LFCSP]	CP-10-9
ADM3062EACPZ-R7	-40°C to +85°C	10-Lead Lead Frame Chip Scale Package [LFCSP]	CP-10-9
ADM3062EBCPZ	-40°C to +125°C	10-Lead Lead Frame Chip Scale Package [LFCSP]	CP-10-9
ADM3062EBCPZ-R7	-40°C to +125°C	10-Lead Lead Frame Chip Scale Package [LFCSP]	CP-10-9
ADM3062EARMZ	-40°C to +85°C	10-Lead Mini Small Outline Package [MSOP]	RM-10
ADM3062EARMZ-R7	-40°C to +85°C	10-Lead Mini Small Outline Package [MSOP]	RM-10
ADM3062EBRMZ	-40°C to +125°C	10-Lead Mini Small Outline Package [MSOP]	RM-10
ADM3062EBRMZ-R7	-40°C to +125°C	10-Lead Mini Small Outline Package [MSOP]	RM-10
ADM3065EARZ	-40°C to +85°C	8-Lead Standard Small Outline Package [SOIC_N]	R-8
ADM3065EARZ-R7	-40°C to +85°C	8-Lead Standard Small Outline Package [SOIC_N]	R-8
ADM3065EBRZ	-40°C to +125°C	8-Lead Standard Small Outline Package [SOIC_N]	R-8
ADM3065EBRZ-R7	-40°C to +125°C	8-Lead Standard Small Outline Package [SOIC_N]	R-8
ADM3065EARMZ	-40°C to +85°C	8-Lead Mini Small Outline Package [MSOP]	RM-8
ADM3065EARMZ-R7	-40°C to +85°C	8-Lead Mini Small Outline Package [MSOP]	RM-8
ADM3065EBRMZ	-40°C to +125°C	8-Lead Mini Small Outline Package [MSOP]	RM-8
ADM3065EBRMZ-R7	-40°C to +125°C	8-Lead Mini Small Outline Package [MSOP]	RM-8
ADM3066EACPZ	-40°C to +85°C	10-Lead Lead Frame Chip Scale Package [LFCSP]	CP-10-9
ADM3066EACPZ-R7	-40°C to +85°C	10-Lead Lead Frame Chip Scale Package [LFCSP]	CP-10-9
ADM3066EBCPZ	-40°C to +125°C	10-Lead Lead Frame Chip Scale Package [LFCSP]	CP-10-9
ADM3066EBCPZ-R7	-40°C to +125°C	10-Lead Lead Frame Chip Scale Package [LFCSP]	CP-10-9
ADM3066EARMZ	-40°C to +85°C	10-Lead Mini Small Outline Package [MSOP]	RM-10
ADM3066EARMZ-R7	-40°C to +85°C	10-Lead Mini Small Outline Package [MSOP]	RM-10
ADM3066EBRMZ	-40°C to +125°C	10-Lead Mini Small Outline Package [MSOP]	RM-10
ADM3066EBRMZ-R7	-40°C to +125°C	10-Lead Mini Small Outline Package [MSOP]	RM-10
EVAL-ADM3061EEBZ		8-Lead SOIC Evaluation Board	
EVAL-ADM3061EEB1Z		8-Lead MSOP Evaluation Board	
EVAL-ADM3062EEBZ		10-Lead MSOP Evaluation Board	
EVAL-ADM3062EEB1Z		10-Lead LFCSP Evaluation Board	
EVAL-ADM3065EEBZ		8-Lead SOIC Evaluation Board	
EVAL-ADM3065EEB1Z		8-Lead MSOP Evaluation Board	
EVAL-ADM3066EEBZ		10-Lead MSOP Evaluation Board	
EVAL-ADM3066EEB1Z		10-Lead LFCSP Evaluation Board	

¹ Z = RoHS Compliant Part.

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